TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74HC237AP,TC74HC237AF

3-to-8 Line Decoder/Latch

The TC74HC237A is a high speed CMOS 3-to-8 LINE DECODER ADDRESS LATCH fabricated with silicon gate C2MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

It is composed of a 3-bit input latches with a common \overline{GL} enable input and 3-to-8 line decoder with enable inputs G1 and $\overline{G2}$. The 3-bit binary data is stored into the input latch on the high level of \overline{GL} . The value of this data determines which one of the outputs will go low.

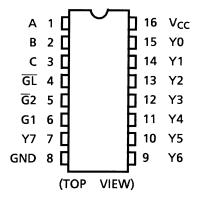
When the enable input G1 is held low or $\overline{G}2$ is held high, decoding function is inhibited and all the 8 outputs go high. The two enable inputs are provided to ease cascade connection and permits the application address decoder for memory system.

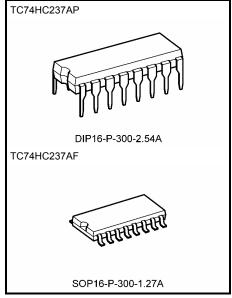
All inputs are equipped with protection circuits against static discharge or transient excess voltage.

Features

- High speed: $t_{pd} = 12 \text{ ns (typ.)}$ at $V_{CC} = 5 \text{ V}$
- Low power dissipation: $ICC = 4 \mu A \text{ (max)}$ at $Ta = 25^{\circ}C$
- High noise immunity: V_{NIH} = V_{NIL} = 28% V_{CC} (min)
- Output drive capability: 10 LSTTL loads
- Symmetrical output impedance: |I_{OH}| = I_{OL} = 4 mA (min)
- Balanced propagation delays: $t_{pLH} \simeq t_{pHL}$
- Wide operating voltage range: V_{CC} (opr) = 2~6 V
- Pin and function compatible with 74LS237

Pin Assignment



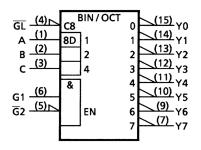


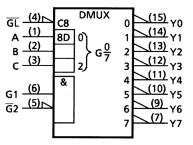
Weight

DIP16-P-300-2.54A : 1.00 g (typ.) SOP16-P-300-1.27A : 0.18 g (typ.)

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IEC Logic Symbol



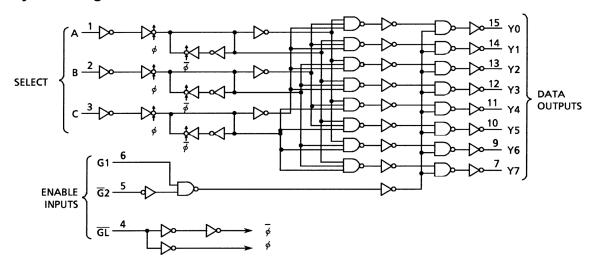


Truth Table

	Inputs							Out	puts				
	Enable			Address	1	Y0	Y1	Y2	Y3	Y4	Y5	Y6	Y7
GL	G2	G1	С	В	Α	10	11	12	13	14	15	10	17
Х	Х	L	Х	Х	Х	L	L	L	L	L	L	L	L
Х	Н	Х	Х	Х	Х	L	L	L	L	L	L	L	L
L	L	Н	L	L	L	Н	L	L	L	L	L	L	L
L	L	Н	L	L	Н	L	Н	L	L	L	L	L	L
L	L	Н	L	Н	L	L	L	Н	L	L	L	L	L
L	L	Н	L	Н	Н	L	L	L	Н	L	L	L	L
L	L	Н	Н	L	L	L	L	L	L	Н	L	L	L
L	L	Н	Н	L	Н	L	L	L	L	L	Н	L	L
L	L	Н	Н	Н	L	L	L	L	L	L	L	Н	L
L	L	Н	Н	Н	Н	L	L	L	L	L	L	L	Н
Н	L	Н	Х	X	Х	Depends upon the address previously applied while GL was at a low level							L was

X: Don't care

System Diagram



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Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V _{CC}	-0.5~7	V
DC input voltage	V _{IN}	-0.5~V _{CC} + 0.5	V
DC output voltage	V _{OUT}	-0.5~V _{CC} + 0.5	V
Input diode current	I _{IK}	±20	mA
Output diode current	lok	±20	mA
DC output current	lout	±25	mA
DC V _{CC} /ground current	Icc	±50	mA
Power dissipation	PD	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T _{stg}	-65~150	°C

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = -40 to 65°C. From Ta = 65 to 85°C a derating factor of -10 mW/°C shall be applied until 300 mW.

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V _{CC}	2~6	V
Input voltage	V _{IN}	0~V _{CC}	V
Output voltage	V _{OUT}	0~V _{CC}	V
Operating temperature	T _{opr}	-40~85	°C
		0~1000 (V _{CC} = 2.0 V)	
Input rise and fall time	t _r , t _f	0~500 (V _{CC} = 4.5 V)	ns
		0~400 (V _{CC} = 6.0 V)	

Note: The operating ranges must be maintained to ensure the normal operation of the device.
Unused inputs must be tied to either VCC or GND.



Electrical Characteristics

DC Characteristics

Characteristics	Symbol	Test Condition			Ta = 25°C			Ta = -40~85°C		Unit
Characteristics	Symbol			V _{CC} (V)	Min	Тур.	Max	Min	Max	Offic
				2.0	1.50	_	_	1.50	_	
High-level input voltage	V _{IH}		_	4.5	3.15	_	_	3.15	_	V
ŭ				6.0	4.20	_	_	4.20	_	
				2.0	_	_	0.50		0.50	
Low-level input voltage	V_{IL}		_	4.5	_	_	1.35	_	1.35	V
				6.0	_	_	1.80		1.80	
		V _{IN} = V _{IH} or V _{IL}		2.0	1.9	2.0	_	1.9	_	
			$I_{OH} = -20 \mu A$	4.5	4.4	4.5	_	4.4	_	
High-level output voltage	VoH			6.0	5.9	6.0	_	5.9	_	V
			$I_{OH} = -4 \text{ mA}$	4.5	4.18	4.31	_	4.13	_	
			$I_{OH} = -5.2 \text{ mA}$	6.0	5.68	5.80	_	5.63	_	
				2.0	_	0.0	0.1	_	0.1	
			$I_{OL} = 20 \ \mu A$	4.5	_	0.0	0.1	_	0.1	
Low-level output voltage	V _{OL}	V _{IN} = V _{IH} or V _{IL}		6.0	_	0.0	0.1	_	0.1	V
			$I_{OL} = 4 \text{ mA}$	4.5	_	0.17	0.26		0.33	
			$I_{OL} = 5.2 \text{ mA}$	6.0	_	0.18	0.26		0.33	
Input leakage current	I _{IN}	$V_{IN} = V_{CC}$ or GND		6.0			±0.1	_	±1.0	μА
Quiescent supply current	Icc	$V_{IN} = V_{CC}$ or	r GND	6.0	_	_	4.0	_	40.0	μА

Timing Requirements (input: $t_r = t_f = 6 \text{ ns}$)

Characteristics	Symbol	Test Condition	Test Condition		Ta = 25°C		Unit	
			V _{CC} (V)	Тур.	Limit	Limit		
Minimum pulse width			2.0	_	75	95		
(GL)	t _{W (L)}	_	4.5	_	15	19	ns	
(GL)			6.0	—	13	16		
Minimum set-up time			2.0	_	50	65		
(A, B, C- GL)	ts	_	4.5	_	10	13	ns	
(A, B, C-GL)			6.0	_	9	11		
Minimum hold time			2.0	_	25	30		
(A, B, C- GL)	t _h	_	4.5	_	5	6	ns	
(A, D, O-GL)			6.0	_	5	5		



AC Characteristics (C_L = 15 pF, V_{CC} = 5 V, Ta = 25°C, input: t_r = t_f = 6 ns)

Characteristics	Symbol	Test Condition		Тур.	Max	Unit
Output transition time	t _{TLH}			4	8	ns
Output transition time	t _{THL}			4	0	115
Propagation delay time	t _{pLH}			12	24	no
(G1-Y)	t _{pHL}	_	_	12	24	ns
Propagation delay time	t _{pLH}			12	24	no
(G 2 -Y)	t _{pHL}	_	_	12	24	ns
Propagation delay time	t _{pLH}			17	33	no
(GL -Y)	t _{pHL}	_	_	17	33	ns
Propagation delay time	t _{pLH}			45	24	
(A, B, C-Y)	t _{pHL}	_		15	31	ns

AC Characteristics ($C_L = 50$ pF, input: $t_r = t_f = 6$ ns)

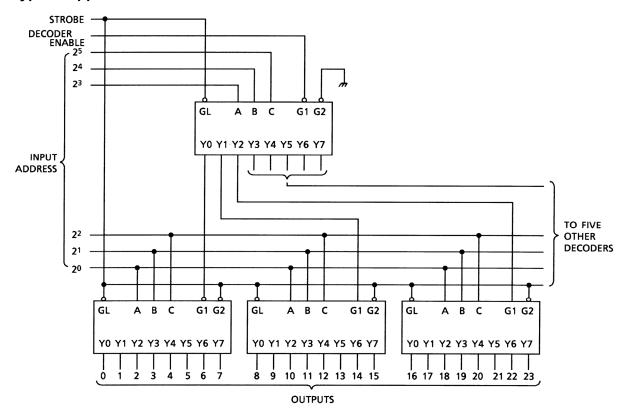
Characteristics	Symbol	Test Condition		-	Ta = 25°C	2	Ta = -40~85°C		Unit
Characteristics	Syllibol		V _{CC} (V)	Min	Тур.	Max	Min	Max	Oill
	t		2.0	_	30	75	_	95	
Output transition time	^t TLH	_	4.5	_	8	15		19	ns
	t _{THL}		6.0		7	13		16	
Propagation delay	t _{pLH}		2.0		45	140		175	
time		_	4.5	_	15	28		35	ns
(G1-Y)	t _{pHL}		6.0		13	24	_	30	
Propagation delay	+		2.0	_	45	140	_	175	
time	t _{pLH}	_	4.5	_	15	28	_	35	ns
(G2 -Y)	t _{pHL}		6.0		13	24	_	30	
Propagation delay	+		2.0		65	190	_	240	
time	t _{pLH}	_	4.5	_	21	38	_	48	ns
(GL -Y)	t _{pHL}		6.0		18	32	_	41	
Propagation delay	t _{pLH}		2.0		60	180	_	225	
time		_	4.5	_	19	36		45	ns
(A, B, C-Y)	t _{pHL}		6.0	_	16	31	_	38	
Input capacitance	C _{IN}				5	10		10	pF
Power dissipation	C _{PD}				52				pF
capacitance	(Note)				32				ρi

Note: CPD is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

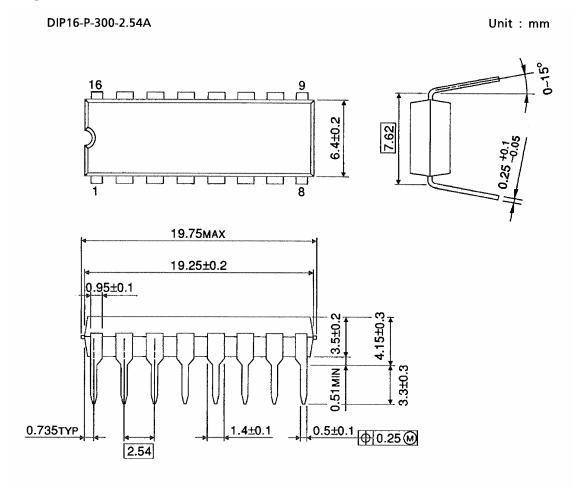
$$I_{CC}$$
 (opr) = $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$

Typical Application



6 Line to 64 Line Decoder with Input Address Storage

Package Dimensions

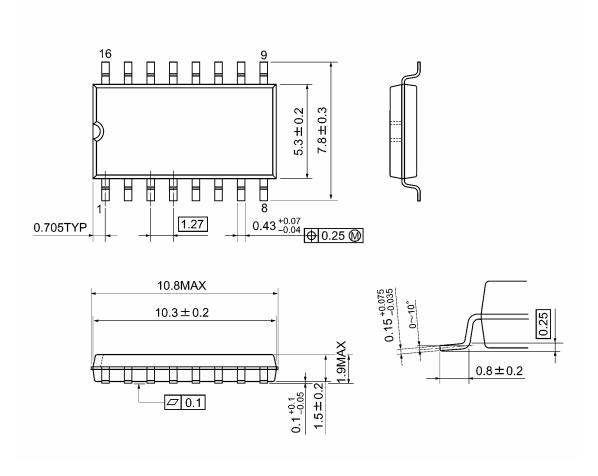


Weight: 1.00 g (typ.)

Package Dimensions

TOSHIBA

SOP16-P-300-1.27A Unit: mm



Weight: 0.18 g (typ.)

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20070701-EN GENERAL

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